

Hong-Dar Lin

List of Publications by Year in descending order

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Version: 2024-02-01

35
papers

413
citations

759233

12
h-index

752698

20
g-index

36
all docs

36
docs citations

36
times ranked

239
citing authors

#	ARTICLE	IF	CITATIONS
1	Multiproduct manufacturer-retailer coordinated supply chain with adjustable rate for common parts, delayed differentiation, and multi-shipment. <i>Uncertain Supply Chain Management</i> , 2022, 10, 83-94.	3.2	1
2	Multi-item fabrication-shipment decision model featuring multi-delivery, postponement, quality assurance, and overtime. <i>Uncertain Supply Chain Management</i> , 2022, 10, 1041-1054.	3.2	2
3	Computer-Aided Industrial Inspection of Vehicle Mirrors Using Computer Vision Technologies. <i>Transactions on Computational Science and Computational Intelligence</i> , 2021, , 263-270.	0.3	0
4	Optical inspection of appearance faults for auto mirrors using Fourier filtering and convex hull arithmetic. <i>Journal of Applied Research and Technology</i> , 2021, 19, 279-293.	0.9	1
5	Effective image models for inspecting profile flaws of car mirrors with applications. <i>Journal of Applied Engineering Science</i> , 2020, 18, 81-91.	0.9	4
6	Creation of image models for inspecting defects in commercial dried fish floss. <i>Journal of Applied Engineering Science</i> , 2020, 18, 393-402.	0.9	1
7	Meeting multiproduct demand with a hybrid inventory replenishment system featuring quality reassurance. <i>Operations Research Perspectives</i> , 2019, 6, 100112.	2.1	9
8	Advanced Artificial Neural Networks. <i>Algorithms</i> , 2018, 11, 102.	2.1	9
9	Creation of image models for inspecting visual flaws on capacitive touch screens. <i>Journal of Applied Engineering Science</i> , 2018, 16, 333-342.	0.9	6
10	Automated visual fault inspection of optical elements using machine vision technologies. <i>Journal of Applied Engineering Science</i> , 2018, 16, 447-453.	0.9	5
11	An Extended EPQ-Based Problem with a Discontinuous Delivery Policy, Scrap Rate, and Random Breakdown. <i>Scientific World Journal, The</i> , 2015, 2015, 1-13.	2.1	2
12	Solving a vendor-buyer integrated problem with rework and a specific multi-delivery policy by a two-phase algebraic approach. <i>Economic Modelling</i> , 2014, 36, 30-36.	3.8	9
13	Combining an improved multi-delivery policy into a single-producer multi-retailer integrated inventory system with scrap in production. <i>Economic Modelling</i> , 2014, 39, 163-167.	3.8	2
14	A note on "intra-supply chain system with multiple sales locations and quality assurance". <i>Expert Systems With Applications</i> , 2013, 40, 4730-4732.	7.6	7
15	An innovative blemish detection system for curved LED lenses. <i>Expert Systems With Applications</i> , 2013, 40, 471-479.	7.6	12
16	Automated quality inspection of surface defects on touch panels. <i>Journal of the Chinese Institute of Industrial Engineers</i> , 2012, 29, 291-302.	0.5	8
17	Note on "replenishment run time problem with machine breakdown and failure in rework". <i>Expert Systems With Applications</i> , 2012, 39, 13070-13072.	7.6	8
18	Automated Flaw Detection for Lens Components. <i>Advanced Science Letters</i> , 2012, 17, 114-121.	0.2	1

#	ARTICLE	IF	CITATIONS
19	Flaw detection of domed surfaces in LED packages by machine vision system. Expert Systems With Applications, 2011, 38, 15208-15216.	7.6	15
20	Numerical method for determination of the optimal lot size for a manufacturing system with discontinuous issuing policy and rework. International Journal for Numerical Methods in Biomedical Engineering, 2011, 27, 1545-1557.	2.1	9
21	Mathematical modeling for solving manufacturing run time problem with defective rate and random machine breakdown. Computers and Industrial Engineering, 2011, 60, 576-584.	6.3	17
22	A hybrid approach based on Hotelling statistics for automated visual inspection of display blemishes in LCD panels. Expert Systems With Applications, 2009, 36, 12332-12339.	7.6	8
23	Automated defect inspection of light-emitting diode chips using neural network and statistical approaches. Expert Systems With Applications, 2009, 36, 219-226.	7.6	32
24	Automated process adjustments of chip cutting operations using neural network and statistical approaches. Expert Systems With Applications, 2009, 36, 4338-4345.	7.6	3
25	A note on optimal replenishment policy for imperfect quality EMQ model with rework and backlogging. Computers and Mathematics With Applications, 2008, 56, 2819-2824.	2.7	27
26	Tiny surface defect inspection of electronic passive components using discrete cosine transform decomposition and cumulative sum techniques. Image and Vision Computing, 2008, 26, 603-621.	4.5	29
27	Automated detection of light-emitting-diode chip surface blemishes on two background textures. Optical Engineering, 2008, 47, 017201.	1.0	3
28	APPLYING DISCRETE COSINE TRANSFORM AND GREY RELATIONAL ANALYSIS TO SURFACE DEFECT DETECTION OF LEDS. Journal of the Chinese Institute of Industrial Engineers, 2007, 24, 458-467.	0.5	10
29	Computer-aided visual inspection of surface defects in ceramic capacitor chips. Journal of Materials Processing Technology, 2007, 189, 19-25.	6.3	41
30	Detection of pinhole defects on chips and wafers using DCT enhancement in computer vision systems. International Journal of Advanced Manufacturing Technology, 2007, 34, 567-583.	3.0	21
31	Automated visual inspection of ripple defects using wavelet characteristic based multivariate statistical approach. Image and Vision Computing, 2007, 25, 1785-1801.	4.5	55
32	Solving an EPQ Model with Rework and Service Level Constraint. Mathematical and Computational Applications, 2006, 11, 75-84.	1.3	13
33	Optimal production lot sizing with backlogging, random defective rate, and rework derived without derivatives. Proceedings of the Institution of Mechanical Engineers, Part B: Journal of Engineering Manufacture, 2006, 220, 1559-1563.	2.4	26
34	Computer-Aided Vision System for MURA-Type Defect Inspection in Liquid Crystal Displays. Lecture Notes in Computer Science, 2006, , 442-452.	1.3	16
35	A T2STATISTICS BASED WAVELET CHARACTERISTIC MULTIVARIATE PROCESSING MODEL APPLIED TO AUTOMATED INSPECTION OF SURFACE DEFECTS. Journal of the Chinese Institute of Industrial Engineers, 2004, 21, 121-135.	0.5	1